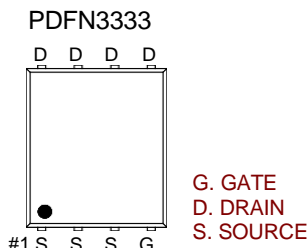


## N -Channel High Density Trench MOSFET

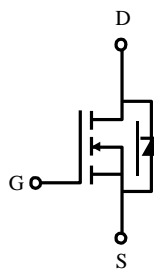
### Features:

- Super high dense cell trench design for low  $R_{DS(on)}$ .
- Rugged and reliable.
- Surface Mount package.



### PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(on)}$ (m $\Omega$ ) Max	$I_D$
40V	6.5 @ $V_{GS} = 10V$	45A
	10.5 @ $V_{GS} = 4.5V$	



### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous	$I_D$	TC=25 $^\circ C$	45
		TC=100 $^\circ C$	29
Pulsed Drain Current (Note 1)	$I_{DM}$	180	A
Avalanche Current	$I_{AS}$	37	
Single Pulse Avalanche Energy	L = 0.1mH	$E_{AS}$	68 mJ
Maximum Power Dissipation (Note 1)	$P_D$	TC=25 $^\circ C$	20.8
		TC=100 $^\circ C$	13.2
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	- 55 to 150	$^\circ C$

### TYPICAL THERMAL CHARACTERISTICS (Note 1)

Thermal Resistance, Junction-to-Case	$R_{thJC}$	6	$^\circ C/W$
Thermal Resistance Junction-Ambient	$R_{thJA}$	65	$^\circ C/W$

Note :

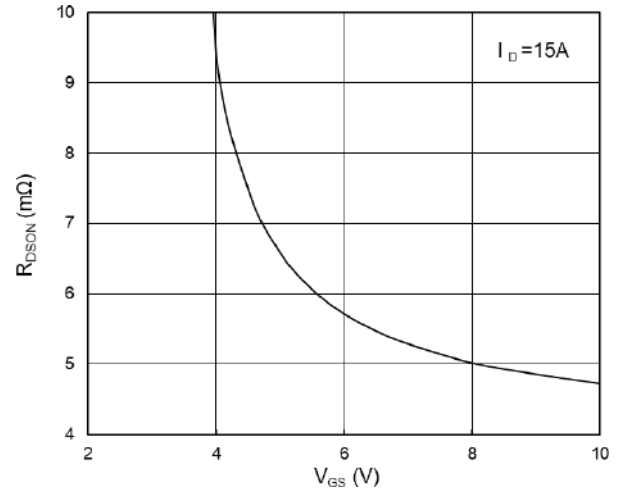
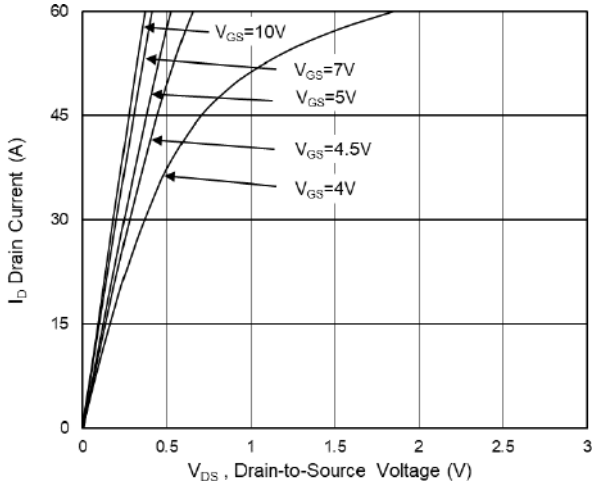
1. Pulse width limited by maximum junction temperature.

**ELECTRICAL CHARACTERISTICS (TA = 25 °C unless otherwise noted)**

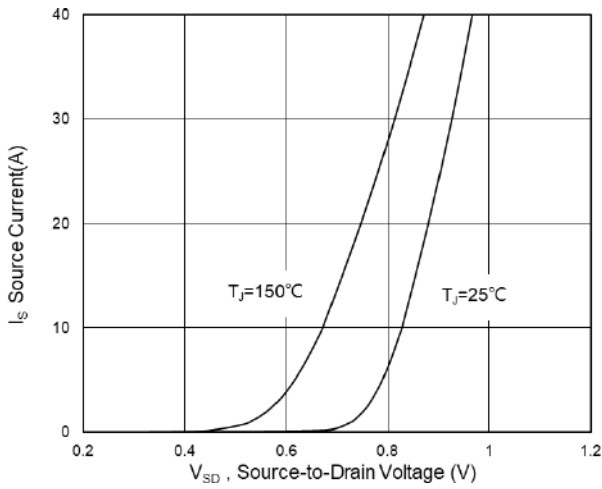
Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	40			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 32V, V_{GS} = 0V, T_j = 25^\circ C$			1	uA
		$V_{DS} = 32V, V_{GS} = 0V, T_j = 100^\circ C$			10	
Gate-Body Leakage	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$			$\pm 100$	nA
<b>ON CHARACTERISTICS (Note 2)</b>						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1	1.8	2.5	V
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 15A$		4.5	6.5	m $\Omega$
		$V_{GS} = 4.5V, I_D = 15A$		8	10.5	m $\Omega$
Forward Transconductance	$g_{fs}$	$V_{DS} = 5V, I_D = 12A$		12		S
<b>DYNAMIC CHARACTERISTICS</b>						
Input Capacitance	$C_{ISS}$	$V_{DS} = 20V, V_{GS} = 0V$ $f = 1.0MHz$		1072		pF
Output Capacitance	$C_{OSS}$			479		pF
Reverse Transfer Capacitance	$C_{RSS}$			49		pF
Gate Resisance	$R_g$	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$		1.9		$\Omega$
<b>SWITCHING CHARACTERISTICS (Note 3)</b>						
Turn-On Delay Time	$t_{d(ON)}$	$V_{DD} = 20V, I_D = 15A, V_{GS} = 10V$ $R_{GS} = 3\Omega$		11.5		nS
Rise Time	$t_r$			9.2		nS
Turn-Off Delay Time	$t_{d(OFF)}$			23.8		nS
Fall Time	$t_f$			15.4		nS
Total Gate Charge (10V)	$Q_g$				19.8	
Total Gate Charge (4.5V)	$Q_g$	$V_{DS} = 20V, I_D = 15A$ $V_{GS} = 10V$		12.5		nC
Gate-Source Charge	$Q_{gs}$			3.9		nC
Gate-Drain Charge	$Q_{gd}$			4.7		nC
<b>DRAIN-SOURCE DIODE CHARACTERISTICS</b>						
Continuous Current	$I_S$			45		A
Diode Forward Voltage (Note 2)	$V_{SD}$	$V_{GS} = 0V, I_S = I_F$		0.75	1.2	V

Note :  
 2. Pulse Test Pulse width  $\leq 300\mu sec$ , Duty Cycle  $\leq 2\%$   
 3. Independent of operating production testing .

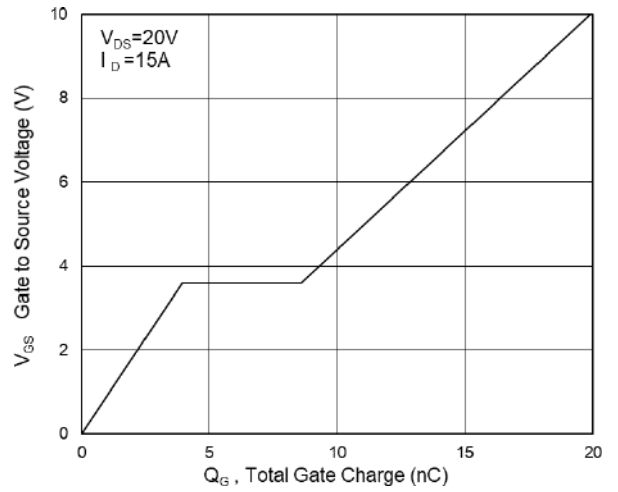
**Typical Characteristics**



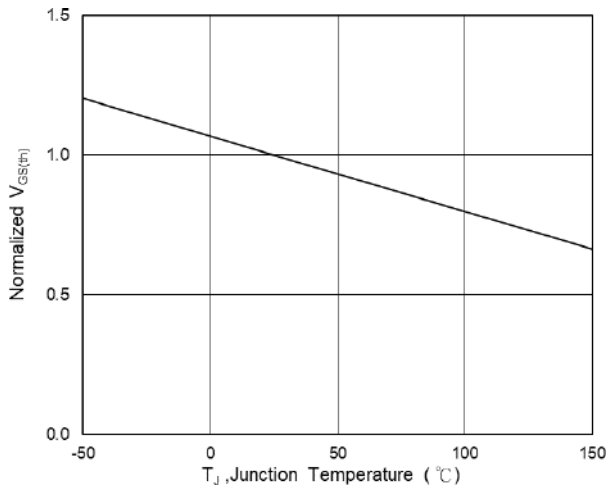
**Typical Output Characteristics**



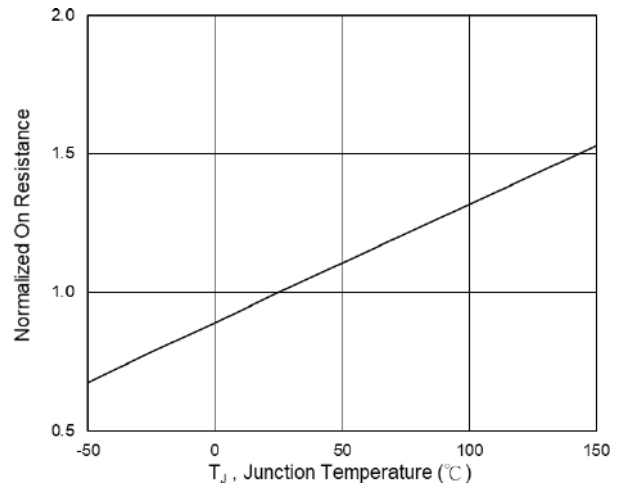
**On-Resistance vs G-S Voltage**



**Source Drain Forward Characteristics**

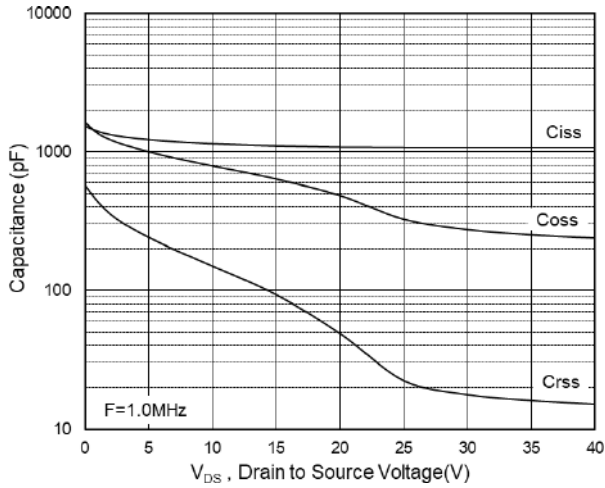


**Gate-Charge Characteristics**

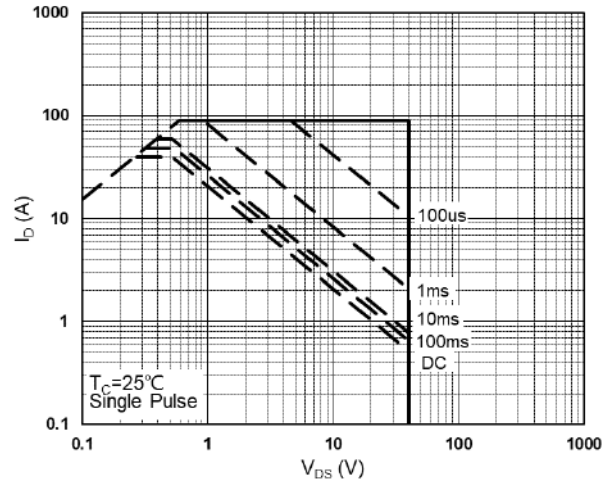


**Normalized  $V_{GS(th)}$  vs  $T_J$**

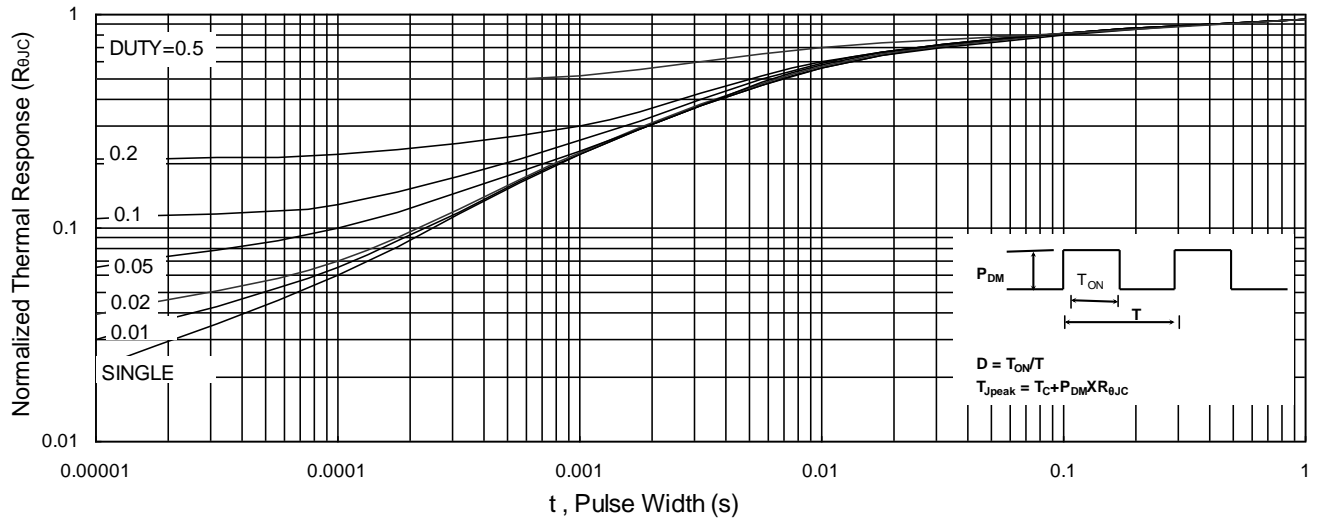
**Normalized  $R_{DS(on)}$  vs  $T_J$**



Capacitance



Safe Operating Area



Normalized Maximum Transient Thermal Impedance